

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**  
Patent Application

Inventor(s): Massimo CIVILINI

Group Art Unit:

Filed: 6/24/03

Examiner:

Serial No.:

Title: AN ELECTRONIC COMPONENT RELIABILITY DETERMINATION SYSTEM AND METHOD

Form 1449**U.S. Patent Documents**

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
	A						
	B						
	C						
	D						
	E						
	F						
	G						
	H						
	I						
	J						
	K						

**Foreign Patent or Published Foreign Patent Application**

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	L							
	M							
	N							
	O							
	P							
	Q							

**Other Documents**

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
SS	R	"SRAM Module; Mean Time Between Failure Analysis (MTBF)," Hybrid Memory Products LTD, February 1999, 11 pages
SS	S	"Reliability Prediction of Board-Mounted Power Modules," Tyco Electronics, Technical Note, July 1997, 6 pages
	T	
Examiner <i>SS</i>		Date Considered 4/20/06

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered.  
 Include copy of this form with next communication to applicant.

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor(s): Massimo CIVILINI

Serial No.:

Group Art Unit:

Filed: 6/24/03

Examiner:

Title: AN ELECTRONIC COMPONENT RELIABILITY DETERMINATION SYSTEM AND METHOD

The Commissioner of Patents and Trademarks  
P.O. Box 1450  
Alexandria, VA 22313-1450  
Sir:

Information Disclosure Statement Submitted Pursuant to 37 C.F.R. 1.97(b)

The citations referenced herein, copies attached, may be material to the examination of the above-identified application and are, therefore, submitted in compliance with the duty of disclosure as defined in 37 C.F.R. 1.56. The Examiner is requested to make these citations of official record in the application.

This Information Disclosure Statement submitted in accordance with 37 C.F.R. 1.97(b) is not to be construed as a representation that a search has been made, that additional items material to the examination of this application do not exist, or that any one or more of these citations constitute prior art under 35 U.S.C. 102.

The Examiner's attention is respectfully directed to the following documents:

<u>Title</u>	<u>Publication Date</u>
"SRAM Module; Mean Time Between Failure Analysis (MTBF)," Hybrid Memory Products LTD, 11 pages	February 1999
"Reliability Prediction of Board-Mounted Power Modules," Tyco Electronics, Technical Note, 6 pages	July 1997

Please direct all correspondence concerning the above-identified application to the following address:

WAGNER, MURABITO & HAO LLP  
Two North Market Street, Third Floor  
San Jose, California 95113  
(408) 938-9060

Respectfully submitted,

Date: 6/24/03By: John F. Ryan

John F. Ryan  
Reg. No. 47,050